GENERAL DESCRIPTION

The MXC3420AL is a small form factor, integrated digital output 3-axis accelerometer with a feature set optimized for industry applications, likes industry automatic control, device motion and tilt monitoring, remote controls, robot controls, etc.

The MXC3420AL features a dedicated motion block which implements algorithms to support "any motion" and shake detection, tilt/flip and tilt 35 position detection.

Low power consumption and small size are inherent in the monolithic fabrication approach, where the MEMS accelerometer is integrated in a single-chip with the electronics integrated circuit.

In the MXC3420AL the internal sample rate can be set from 128 to 1024 samples / second. The device supports the reading of sample and event status via polling or interrupts.

FEATURES

Range, Sampling & Power

- $\pm 2, \pm 4, \pm 8, \pm 12, \pm 16$ g range
- 16-bit resolution
- 128 to 1024 Output Data Rate
- 4 μA typical Standby current
- Low typical active current

Simple System Integration

- I2C interface, up to 1 MHz
- 2×2×0.92 mm 12-pin LGA package
- High reliability thru single-chip 3D silicon MEMS technology
- Mechanical Shock 20000G
- RoHS compliant

Applications

- Industrial automatic control
- Smart robot controls
- Motion and tilt monitoring
- Remote controls
- Alarm module

Information furnished by MEMSIC is believed to be accurate and reliable. However, no responsibility is assumed by MEMSIC for its use, or for any infringements of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of MEMSIC.

www.memsic.com

TABLE OF CONTENTS

1 ORDER INFORMATION

Table 1. Order Information

Table 2. Package Information

Page 4 of 53 2020/08

2 FUNCTIONAL BLOCK DIAGRAM

Figure 1. Block Diagram

3 PACKAGING AND PIN DESCRIPTION

3.1 PACKAGE OUTLINE

 $SYMBOL$ MIN. NOM. MAX. A $\Big| 0.85 \Big| 0.92 \Big| 1.00$ 2.00 BSC 2.00 BSC 0.5 BSC e1 0.5125 REF b $\vert 0.20 \vert 0.25 \vert 0.30$ L1 $\begin{array}{|c|c|c|c|c|c|c|c|c|} \hline \end{array}$ 0.05 0.10 0.15 L | 0.225 | 0.275 | 0.325 \boxed{D} E \boxed{e}

DIMENSION (MM)

Figure 2. Package Outline and Mechanical Dimensions

3.2 PACKAGE ORIENTATION

Figure 3. Package Orientation

Figure 4. Package Axis Reference

```
MEMSIC MXC3420AL Datasheet V1.0 Page 7 of 53 2020/08
```
3.3 PIN DESCRIPTION

Table 3. Pin Description

Notes:

- 1) This pin requires a pull-up resistor, typically 4.7kΩ to pin VDD/VDDIO. Refer to I2C Specification for Fast-Mode devices. Higher resistance values can be used (typically done to reduce current leakage) but such applications are outside the scope of this datasheet.
- 2) This pin can be configured by software to operate either as an open-drain output or push-pull output (**[mode register](#page-30-0)**). If set to open-drain, then it requires a pull-up resistor, typically 4.7kΩ to VDD/VDDIO.
- 3) INTN pin polarity is programmable in the **[mode register](#page-30-0)**.

3.4 TYPICAL APPLICATION CIRCUITS

NOTE¹: Rp are typically 4.7kΩ pullup resistors to VDD/VDDIO, per I2C specification. When pin VDD/VDDIO is powered down, SDA and SCL will be driven low by internal ESD diodes. NOTE²: Attach typical 4.7kΩ pullup resistor if INTN is defined as open-drain.

Figure 5. Typical Application Circuit for 3DOF Solution

In typical applications, the interface power supply may contain significant noise from external sources and other circuits which should be kept away from the sensor. Therefore, for some applications a lower-noise power supply might be desirable to power the VDD/VDDIO pin.

3.5 TAPE AND REEL

Devices are shipped in reels, in standard cardboard box packaging. See **[Figure 6.](#page-9-1) [MXC3420AL Tape Dimensions](#page-9-1)** and **Figure 7. [MXC3420AL Reel Dimensions](#page-10-0)**.

- Dimensions in mm.
- 10 sprocket hole pitch cumulative tolerance ±0.2
- Pocket position relative to sprocket hole measured as true position of pocket, not pocket hole.

Figure 6. MXC3420AL Tape Dimensions

• Dimensions in mm.

Figure 7. MXC3420AL Reel Dimensions

3.6 SOLDERING PROFILE

The LGA package follows the reflow soldering classification profiles described in *Joint Industry Standard, Moisture/Reflow Sensitivity Classification for Nonhermetic Surface Mount Devices*, document number J-STD-020E. Reflow soldering has a peak temperature (T_p) of 260^oC

3.7 SHIPPING AND HANDLING GUIDELINES

Shipping and handling follow the standards described in *Joint Industry Standard, Handling, Packing, Shipping and Use of Moisture/Reflow Sensitive Surface Mount Devices*, document number J-STD-033C.

The following are additional handling guidelines (refer to the MEMSIC document, PCB Design, Device Handling and Assembly Guidelines, for more information):

- While the mechanical sensor is designed to handle high-g shock events, direct mechanical shock to the package should be avoided.
- SMT assembly houses should use automated assembly equipment with either plastic nozzles or nozzles with compliant tips (for example, soft rubber or silicone).
- Avoid g-forces beyond the specified limits during transportation.
- Handling and mounting of sensors should be done in a defined and qualified installation.

3.8 MOISTURE SENSITIVITY LEVEL CONTROL

The following are storage recommendations (refer to the MEMSIC document, PCB Design, Device Handling and Assembly Guidelines, for more information):

- Store the tape and reel in the *unopened* dry pack, until required on the assembly floor.
- If the dry pack has been opened or the reel has been removed from the dry pack, reseal the reel inside of the dry pack with a black protective belt. Avoid crushing the tape and reel.
- Store the cardboard box in a vertical position.

4 SPECIFICATIONS

4.1 ABSOLUTE MAXIMUM RATINGS

Parameters exceeding the Absolute Maximum Ratings may permanently damage the device.

Table 4. Absolute Maximum Ratings

4.2 SENSOR CHARACTERISTICS

Table 5. Sensor Characteristics

4.3 ELECTRICAL AND TIMING CHARACTERISTICS

4.3.1 ELECTRICAL POWER AND INTERNAL CHARACTERISTICS

Test condition: $VDD = 2.8V$, $T_{op} = 25 {}^{o}C$ unless otherwise noted

Table 6. Electrical Characteristics

4.3.2 I2C ELECTRICAL CHARACTERISTICS

Table 7. I2C Electrical and Timing Characteristics

NOTES:

- If multiple slaves are connected to the I2C signals in addition to this device, only 1 pullup resistor on each of SDA and SCL should exist. Also, care must be taken to not violate the I2C specification for capacitive loading.
- When pin VDD/VDDIO is not powered and set to 0V, INTN, SDA and SCL will be held to VDD plus the forward voltage of the internal static protection diodes, typically about 0.6V.
- When pin VDD/VDDIO is disconnected from power or ground (e.g. Hi-Z), the device may become inadvertently powered up through the ESD diodes present on other powered signals.

4.3.3 I2C TIMING CHARACTERISTICS

Figure 8. I2C Interface Timing

Table 8. I2C Timing Characteristics

NOTE: Values are based on I2C Specification requirements, not tested in production.

See also Section [10.3](#page-24-0) **[I2C Message Format](#page-24-0)**.

5 GENERAL OPERATION

The device supports the reading of samples and device status upon interrupt or by polling.

5.1 SENSOR SAMPLING

In the WAKE state, acceleration data for X, Y, and Z axes is sampled at a rate between 31 and 998 samples/second. See the **[Sample Rate Register](#page-31-0)** section.

The detectable acceleration range is variable and is set in the RANGE bits of the **[range and](#page-36-0) [scale control register](#page-36-0)**.

Table 9. Summary of Resolution, Range, and Scaling

5.2 OFFSET AND GAIN CALIBRATION

Digital offset and gain calibration can be performed on the sensor, if necessary, in order to reduce the effects of post-assembly influences and stresses which may cause the sensor readings to be offset from their factory values.

MEMSIC MXC3420AL Datasheet V1.0 Page 19 of 53 2020/08

6 OPERATIONAL STATES

The device has two states of operation: STANDBY and WAKE. All states are controlled by the software, there is no automatic power control.

The device defaults to the STANDBY state following a power-up and must be in the WAKE state before executing a reset.

The time to change from the STANDBY to WAKE state takes one sample period (takes less than 10 μ s).

Table 10. Operational States

7 OPERATIONAL STATE FLOW

[Figure 9. Operational State Flow](#page-20-1) shows the operational state flow for the device. The device defaults to STANDBY following power-on.

Figure 9. Operational State Flow

The operation state may be read from the STATE bits of the **[device status register](#page-28-0)**. The operational state may be forced to a specific state by writing into the STATE bits of the **[mode](#page-30-0) [register](#page-30-0)**, as shown below. Two bits are specified in order to promote software compatibility with other MEMSIC devices. The operational state will stay in the mode specified until changed.

Action	Setting	Effect
Force STANDBY State	$STATE[1:0] = 00$	Switch to the STANDBY state and stay there
		Disable sensor and event sampling
Force WAKE State	$STATE[1:0] = 01$	Switch to WAKE state and stay there
		Continuous sampling

Table 11. Forcing Operational States

8 INTERRUPTS

The sensor device utilizes output pin INT*n* to signal to an external microprocessor that an event has been detected. The microprocessor should contain an interrupt service routine which would perform certain tasks after receiving this interrupt and reading the associated status bits, perhaps after a sample was made ready. If interrupts are to be used, the microprocessor must set up the registers in the sensor so that when a specific event is detected, the microprocessor would receive the interrupt and the interrupt service routine would be executed. If polling is used, there is no need for the interrupt registers to be set up.

For products that use polling, the microprocessor must periodically poll the sensor and read the status data (the INT*n* pin is not used). For most applications, this is likely best done at the sensor sampling rate or faster.

NOTE: At least one I2C STOP condition must be present between samples in order for the sensor to update the sample data registers.

8.1 ENABLING AND CLEARING INTERRUPTS

The **[interrupt status register](#page-35-0)** contains the flag bits for the sample acquisition interrupt ACQ_INT. The **[interrupt enable register](#page-29-0)** determines if a flag event generates interrupts.

The flags (and interrupts) are cleared and rearmed every time an interrupt status register is read.

When an event is detected, it is masked with a flag bit in the interrupt enable register, and then the corresponding status bit is set in the status registers.

The polarity and driving mode of the external interrupt signal may be chosen by setting the IPP and IAH bits in the **[mode register](#page-30-0)**.

8.2 ACQ_INT INTERRUPT

The ACQ_INT flag bit in the status registers is always active. This bit is cleared when it is read. When a sample has been produced, an interrupt will be generated only if the ACQ INT EN bit in the interrupt enable register is active. The frequency of the ACQ INT bit being set active is always the same as the sample rate.

9 SAMPLING

9.1 CONTINUOUS SAMPLING

The device has the ability to read all sampled readings in a continuous sampling fashion. The device always updates the XOUT, YOUT, and ZOUT registers at the chosen ODR.

An optional interrupt can be generated each time the sample registers have been updated (using the ACQ_INT bit in the **[interrupt enable register](#page-29-0)**). See the **[ACQ_INT Interrupt](#page-21-2)** section or **[status register](#page-35-0)** for more information about ACQ_INT.

10 I2C INTERFACE

10.1 PHYSICAL INTERFACE

The I2C slave interface operates at a maximum speed of 1 MHz. The SDA (data) is an opendrain, bi-directional pin and the SCL (clock) is an input pin.

Note: The device always operates as an I2C slave.

An I2C master initiates all communication and data transfers and generates the SCL clock that synchronizes the data transfer. The I2C device address depends upon the state of the VPP pin during power-up as shown in the table below. After the I2C address is selected, it won't changed unless excuting one power on reset.

An optional I2C watchdog timer can be enabled to prevent bus stall conditions. See the **[Watchdog Timer](#page-24-1)** section for more information.

Table 12. I2C Address Selection

The I2C interface remains active as long as power is applied to the VDD/VDDIO pin. In the STANDBY state, the device responds to I2C read and write cycles, but interrupts cannot be serviced or cleared. All registers can be written in the STANDBY state, but in the WAKE state, only the **[mode register](#page-30-0)** can be modified (see the **[Operational States](#page-19-0)** section for more information).

Internally, the registers which are used to store samples are clocked by the sample clock gated by I2C activity. Therefore, in order to allow the device to collect and present samples in the sample registers, at least one I2C STOP condition must be present between samples.

Refer to the I2C specification for a detailed discussion of the protocol. Per I2C requirements, SDA is an open drain, bi-directional pin. SCL and SDA each require an external pull-up resistor, typically 4.7kΩ.

10.2 TIMING

See the **I2C [Timing Characteristics](#page-16-0)** section for I2C timing requirements.

MEMSIC MXC3420AL Datasheet V1.0 Page 24 of 53 2020/08

10.3 I2C MESSAGE FORMAT

Note: At least one I2C STOP condition must be present between samples in order for the sensor to update the sample data registers.

The device uses the following general format for writing to the internal registers: The I2C master generates a START condition and then supplies the 7-bit device ID. The 8th bit is the R/W# flag (write cycle = 0). The device pulls SDA low during the 9th clock cycle indicating a positive ACK.

The second byte is the 8-bit register address of the device to access. The last byte is the data to write.

Figure 10. I2C Message Format, Write Cycle, Single Register Write

In a read cycle, the I2C master generates a START condition and then writes the device ID, R/W# flag (write cycle = 0), and register address. The master issues a RESTART condition and then writes the device ID with the R/W# flag set to '1'. The device shifts out the contents of the register address.

Figure 11. I2C Message Format, Read Cycle, Single Register Read

The I2C master may write or read consecutive register addresses by writing or reading additional bytes after the first access. The device will internally increment the register address.

10.4 WATCHDOG TIMER

The I2C watchdog timer, when enabled (see the **[mode register](#page-30-0)**), prevents bus stall conditions when the master does not provide enough clocks to the slave to complete a read cycle. The I2C watchdog timer does not resolve why the master did not provide enough clocks to complete a read cycle, but it does prevent a slave from holding the bus indefinitely.

During a read cycle, the slave that is actively driving the bus (SDA pin) does not release the bus until nine SCL clock edges are detected. While the SDA pin is held low by a slave opendrain output, any other I2C devices attached to the bus will not be able to communicate. If the

MEMSIC MXC3420AL Datasheet V1.0 Page 25 of 53 2020/08

slave does not see nine SCL clocks from the master within the timeout period (about 200 ms), the slave assumes a system problem has occurred and resets the I2C circuitry, releases the SDA pin, and readies the sensor for additional I2C commands.

When an I2C watchdog timer event is triggered, the I2C_WDT bit in the **[device status](#page-28-0) [register](#page-28-0)** is activated by the Watchdog timer hardware. No other registers are changed. External software can detect this activation by reading the I2C WDT bit. Reading the interrupt status register (**[0x14](#page-35-0)**) clears the I2C_WDT bit.

11 REGISTER INTERFACE

The device has a register interface which allows an MCU or I2C master to configure and monitor all aspects of the device. This section lists an overview of user programmable registers. By convention, bit 0 is the least significant bit (LSB) of a byte register.

11.1 REGISTER SUMMARY

NOTE: Registers are not updated with new event status or samples while an I2C cycle is in process.

MEMSIC MXC3420AL Datasheet V1.0 Page 27 of 53 2020/08

¹ 'R' registers are read-only, via external I2C access. 'W' registers are read-write, via external I2C access.

 2 Registers designated as 'RESERVED' should not be accessed by software.

 3 Software must write a zero (0) to this bit.

 4 Software must write a one (1) to this bit.

Table 13. Register Summary

MEMSIC MXC3420AL Datasheet V1.0 Page 28 of 53 2020/08

11.2 DEVICE STATUS REGISTER

The device status register reports various conditions of the sensor circuitry.

Table 14. Device Status Register

11.3 INTERRUPT ENABLE REGISTER

The interrupt enable register enables or disables the reporting of interrupt status for each interrupt source.

Table 15. Interrupt Enable Register

11.4 MODE REGISTER

The mode register controls the active operating state of the accelerometer. This register can be written from all operational states (WAKE, or STANDBY).

Table 16. Mode Register States

11.5 SAMPLE RATE REGISTER

The sample rate register sets the sampling output data rate (ODR) for the sensor, the clock frequency of the main oscillator, and the oversampling ratio (OSR).

Table 17. Sample Rate Register

11.6 MOTION CONTROL REGISTER

The motion control register enables the flags and interrupts for motion detection features.

Table 18. Motion Control Register

11.7 XOUT, YOUT AND ZOUT DATA ACCELEROMETER REGISTERS

X, Y, and Z-axis accelerometer measurements in 14-bit and 16-bit resolutions and are in a signed 2's complement format. In raw bypass mode (RBM), the 14-bit value is used.

Table 19. Accelerometer LSB and MSB Registers

11.8 STATUS REGISTER

The status register contains the flag and status bits for sample acquisition and motion detection.

Table 20. Status Register

11.9 INTERRUPT STATUS REGISTER

The interrupt status register reports the status of any pending interrupt sources. Each interrupt source must be enabled by the corresponding interrupt enable bit in register 0x06. All interrupts are cleared each time this register is read.

Table 21. Interrupt Status Register

11.10 RANGE AND SCALE CONTROL REGISTER

The range and scale control register sets the resolution, range, and filtering options for the accelerometer. All values are in sign-extended 2's complement format. Values are reported in registers 0x0D – 0x12 (the hardware formats the output).

Table 22. Range and Scale Control Register

11.11 X-AXIS DIGITAL OFFSET REGISTERS

The X-axis digital offset registers contains a signed 2's complement 14-bit value used to offset the output of the X-axis filter. These registers are loaded from the OTP at device initialization and POR. If necessary, these values can be overwritten by software.

Register 0x22 bit 7 is the ninth bit of X-axis gain (XGAIN). See **[X-Axis Digital Gain Registers](#page-40-0)** for more information about XGAIN.

NOTE: When modifying these registers with new gain or offset values, software should perform a read-modify-write type of access to ensure that unrelated bits do not get changed.

Table 23. X-Axis Digital Offset Registers

11.12 Y-AXIS DIGITAL OFFSET REGISTERS

The Y-axis digital offset registers contains a signed 2's complement 14-bit value used to offset the output of the Y-axis filter. These registers are loaded from the OTP at device initialization and POR. If necessary, these values can be overwritten by software.

Register 0x24 bit 7 is the ninth bit of Y-axis gain (YGAIN). See **[Y-Axis Digital Gain Registers](#page-41-0)** for more information about YGAIN.

NOTE: When modifying these registers with new gain or offset values, software should perform a read-modify-write type of access to ensure that unrelated bits do not get changed.

Table 24. Y-Axis Digital Offset Registers

11.13 Z-AXIS DIGITAL OFFSET REGISTERS

The Z-axis digital offset registers contains a signed 2's complement 14-bit value used to offset the output of the Z-axis filter. These registers are loaded from the OTP at device initialization and POR. If necessary, these values can be overwritten by software.

Register 0x26 bit 7 is the ninth bit of Z-axis gain (ZGAIN). See **[Z-Axis Digital Gain Registers](#page-42-0)** for more information about ZGAIN.

NOTE: When modifying these registers with new gain or offset values, software should perform a read-modify-write type of access to ensure that unrelated bits do not get changed.

Table 25. Z-Axis Digital Offset Registers

11.14 X-AXIS DIGITAL GAIN REGISTERS

The X-axis digital gain registers contains an unsigned 9-bit value. These registers are loaded from the OTP at device initialization and POR. If necessary, these values can be overwritten by software.

Register 0x22 bit 7 is the ninth bit of XGAIN.

NOTE: When modifying these registers with new gain values, software should perform a readmodify-write type of access to ensure that unrelated bits do not get changed.

Table 26. X-Axis Digital Gain Registers

11.15 Y-AXIS DIGITAL GAIN REGISTERS

The Y-axis digital gain registers contains an unsigned 9-bit value. These registers are loaded from the OTP at device initialization and POR. If necessary, these values can be overwritten by software.

Register 0x24 bit 7 is the ninth bit of YGAIN.

NOTE: When modifying these registers with new gain values, software should perform a readmodify-write type of access to ensure that unrelated bits do not get changed.

Table 27. Y-Axis Digital Offset Registers

11.16 Z-AXIS DIGITAL GAIN REGISTERS

The Z-axis digital gain registers contains an unsigned 9-bit value. These registers are loaded from the OTP at device initialization and POR. If necessary, these values can be overwritten by software.

Register 0x26 bit 7 is the ninth bit of ZGAIN.

NOTE: When modifying these registers with new gain values, software should perform a readmodify-write type of access to ensure that unrelated bits do not get changed.

Table 28. Z-Axis Digital Offset Registers

11.17 TILT/FLIP THRESHOLD REGISTERS

The tilt/flip threshold registers are used for both the flat/tilt/flip and tilt-35 algorithms.

For the flat/tilt/flip algorithm, these registers hold the programmed 15-bit threshold value to detect the flat/tilt/flip position of the device. If the sample value is greater than the programmed value of these registers, a tilt condition is detected. If the sample value is less than the programmed value of these registers, a flat/flip condition is detected. A flat/flip condition is dependent on the Z-axis value and the Z-axis orientation bit (register 0x09, bit 5).

For the tilt-35 algorithm, these registers hold the programmed 15-bit threshold value that defines the amount of tilt to detect. When the programmed tilt is detected, the tilt-35 interrupt is set in the interrupt status registers (register 0x14, bit 4).

Table 29. Tilt/Flip Threshold Registers

11.18 TILT/FLIP DEBOUNCE REGISTER

The tilt/flip debounce register holds the programmed 8-bit duration of a tilt/flip. When a tilt/flip condition is detected and the duration of the condition is greater than the programmed value of this register, the tilt/flip interrupt is set in the interrupt status registers (register 0x14, bits 0 and 1).

Table 30. Tilt/Flip Debounce Register

11.19 ANYMOTION THRESHOLD REGISTERS

The Anymotion threshold registers hold the programmed 15-bit threshold value to detect a change in the position of the device. If the change in position between the current sample value and previous sample value on any axis is greater than the programmed value of this register, an AnyMotion condition is detected. When the change in position exceeds the programmed AnyMotion threshold, the AnyMotion interrupt is set in the interrupt status registers (register 0x14, bit 2).

Table 31. AnyMotion Threshold Registers

11.20 ANYMOTION DEBOUNCE REGISTER

The AnyMotion debounce register holds the programmed 8-bit duration of any motion. After an AnyMotion condition is detected, if another AnyMotion condition is not detected for the programmed duration, the AnyMotion interrupt is cleared in the interrupt status registers (register 0x14, bits 0 and 1).

Table 32. AnyMotion Debounce Register

MEMSIC MXC3420AL Datasheet V1.0 Page 47 of 53 2020/08

11.21 SHAKE THRESHOLD REGISTERS

The shake threshold registers hold the programmed 15-bit threshold value to detect a shake. If the change in position between the current sample value and previous sample value on any axis is greater than the programmed value of this register, a shake condition is detected.

Table 33. Shake Threshold Registers

11.22 SHAKE DURATION, PEAK-TO-PEAK REGISTERS

The shake duration and peak-to-peak registers hold the programmed 12-bit threshold value of a peak and the peak-to-peak width of a shake and the programmed 3-bit threshold value of the shake counter.

The data in these registers and the shake threshold registers is used to determine if the shake interrupt should be set.

If a shake condition is detected, the shake counter is incremented and the shake's peak is detected and measured. If the peak's width is greater than the peak threshold set in this register, the shake counter continues to increment (measuring the duration of the peak event). When a shake condition is no longer detected, the peak-to-peak event is measured and the shake counter continues to increment (measuring the duration of the peak-to-peak event). When the peak-to-peak threshold is surpassed, the shake counter continues to increment, measuring the duration of the peak event. The shake counter continues to increment each time a peak or peak-to-peak threshold is surpassed. When the shake counter threshold is surpassed, the shake interrupt is set in the interrupt status registers (register 0x14, bit 3).

Table 34. Shake Duration and Peak-to-Peak Registers

11.23 TIMER CONTROL REGISTER

The timer control register sets the period or duration of two features driven by the 10 Hz low speed clock.

Table 35. Timer Control Register

12 INDEX OF TABLES

13 REVISION HISTORY

单击下面可查看定价,库存,交付和生命周期等信息

[>>MEMSIC](https://www.oneyac.com/brand/3295.html)